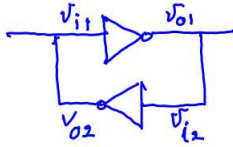
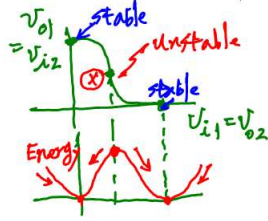


Bistable Latch

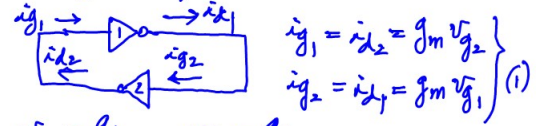


Two stable points

$(V_{i1} = V_{o2} = V_{DD}, V_{o1} = V_{i2} = 0)$
 $\& (V_{i1} = V_{o2} = 0, V_{o1} = V_{i2} = V_{DD})$
 The point where $V_{i1} (= V_{o2}) = V_{o1} (= V_{i2})$ is unstable



Small signal analysis at \otimes .



$$v_{g1} = \frac{g_1}{C_g} \quad v_{g2} = \frac{g_2}{C_g} \quad \dots \dots \dots (2)$$

$$\text{also } \left. \begin{aligned} i_{g1} &= C_g \frac{dv_{g1}}{dt} \\ i_{g2} &= C_g \frac{dv_{g2}}{dt} \end{aligned} \right\} \dots \dots \dots (3)$$

$$\text{From (1) \& (3)} \quad \left. \begin{aligned} g_m v_{g2} &= C_g \frac{dv_{g1}}{dt} \\ g_m v_{g1} &= C_g \frac{dv_{g2}}{dt} \end{aligned} \right\} \dots \dots \dots (4)$$

From (4)

$$g_m v_{g2} = C_g \frac{dv_{g1}}{dt} = C_g \frac{d}{dt} \left(\frac{C_g}{g_m} \frac{dv_{g2}}{dt} \right)$$

$$g_m v_{g2} = \frac{C_g^2}{g_m} \frac{d^2 v_{g2}}{dt^2}$$

$$\frac{d^2 v_{g2}}{dt^2} - \left(\frac{g_m}{C_g} \right)^2 v_{g2} = 0$$

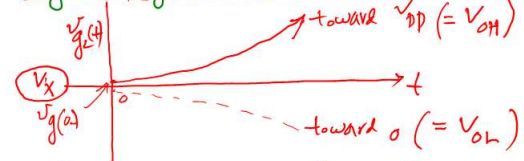
$$\text{let } \frac{1}{\tau} = \frac{g_m}{C_g}, \text{ then } \frac{d^2 v_{g2}}{dt^2} - \left(\frac{1}{\tau} \right)^2 v_{g2} = 0$$

solving for v_{g2} by Laplace transformation

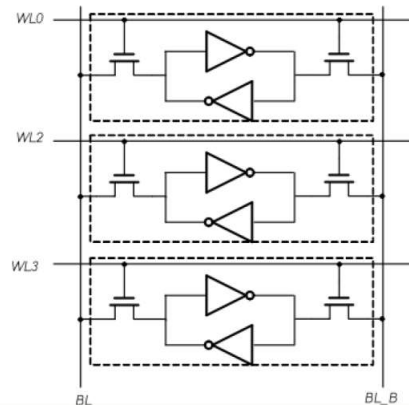
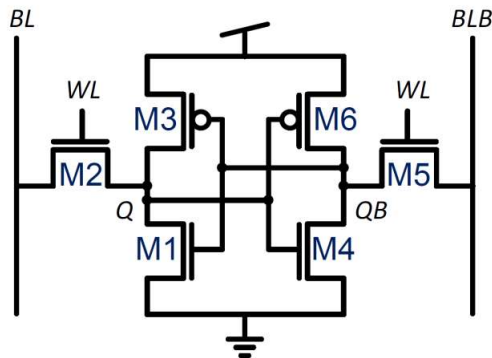
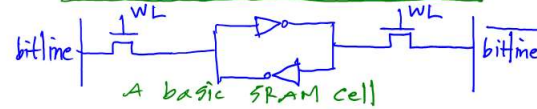
$$s^2 v_{g2}(s) - s v_{g2}(0) - v_{g2}'(0) - \left(\frac{1}{\tau} \right)^2 v_{g2}(s) = 0$$

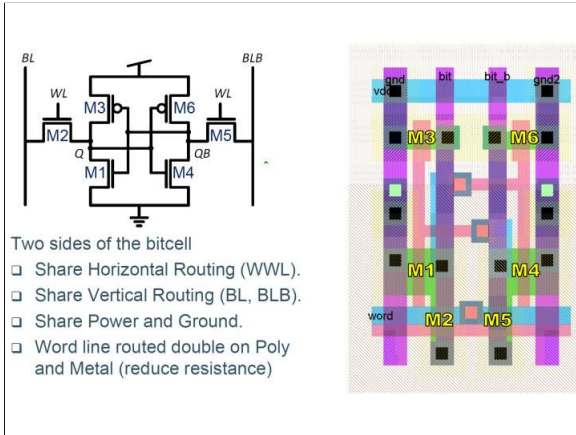
$$\text{For } v_{g2}'(0) = 0 \quad v_{g2}(s) = \frac{s v_{g2}(0)}{s^2 - \left(\frac{1}{\tau} \right)^2} = \frac{1}{2} v_{g2}(0) \left[\frac{1}{s + \frac{1}{\tau}} + \frac{1}{s - \frac{1}{\tau}} \right]$$

$$\Rightarrow v_{g2}(t) = \frac{1}{2} v_{g2}(0) \left(e^{-t/\tau} + e^{+t/\tau} \right)$$



Thus \otimes is an unstable point
any perturbation will lead to migration
to a stable point (V_{OH} or V_{OL})





CMOS Performance Optimization

- Sizing: Optimal performance with equal fan-out per stage
- Extendable to general logic cone through "logical effort"
- Equal effective fan-outs ($\rho C_{in}/C_i$) per stage
- Example: memory decoder

(Ref: I. Sutherland, Morgan-Kaufman '96)

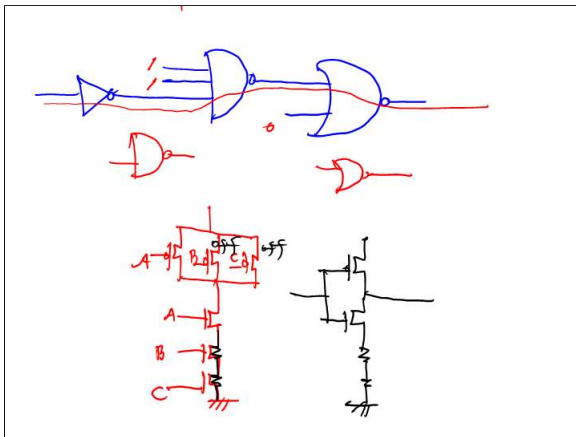
Slide 3.38

This philosophy is best reflected in the popular "logical effort"-based design optimization methodology.

The delay of a circuit is minimized if the "effective fan-out" of each stage is made equal (and set to a value of approximately 4). Though this technique is very powerful, it also guarantees that power consumption is optimal.

In the coming chapters, we will reformulate the logical-effort methodology to bring power into the equation.

* Logical Effort: Designing Fast CMOS Circuits
by Ivan Sutherland, David Sponof, David Harris
Morgan Kaufmann Publishers, 1999



Power Minimization

$$P = C V_{DD} \Delta V_{swing} f_{clock}$$

Full swing case: $C V_{DD}^2 f_{clock}$

For a given f_{clock} ,

$$\min P = C V_{DD}^2 f_{clock}$$

subject to delay < delay specification

⇒ reduce C, V_{DD} (big influence)

delay $\propto \frac{C V_{DD}}{W}$, $C = f(W \text{ (tr. size), interconnect})$

Increasing W reduces delay, but increase C, thus P

$$P = V_{DD} \cdot I$$

$$I = \frac{C \Delta V}{T} = C \Delta V f_{clock}$$

Sub-threshold SRAM

Sub- V_{TH} operation demonstrated in 65 nm memory chip

256 kb SRAM Array

Slide 11.28

A 256 kb SRAM memory was designed and tested using the cell of the previous slide. Reliable operation down to 400 mV was demonstrated.

Though this represents great progress, it is clear that addressing further voltage scaling of SRAMs (or any other memory type) is essential if ultra low power design is to be successful. (sorry if this starts to sound like a broken record!)

- Chip functions without error to below 400 mV, holds without error to below 250 mV.
- At 400 mV, 3.28 mW and 475 kHz at 27°C
- Reads to 320 mV (27°C) and 360 mV (65°C)
- Writes to 380 mV (27°C) and 350 mV (65°C)

(Ref: B. Calhoun, ISSCC'06)

Importance of Low-Level Analysis

Thermal map

clock

data

latch

too much delay

when delays (one at higher temperature) can cause malfunction of a latch!

can latch 0 instead of 1 (error)